

Reversing trick for yield prediction model based on deep learning

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ABSTRACT

In the semiconductor industry, Mathematical modeling techniques are used to find yield prediction models. Recently there have been attempts to apply deep learning method in the semiconductor industry because it requires multiple process parameters and their relations are unknown. This study will focus on the utilization of the yield prediction model based on deep learning. We experimented with MNIST dataset to find the optimal process conditions for the highest yield by using reversing tricks.

REFERENCES

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